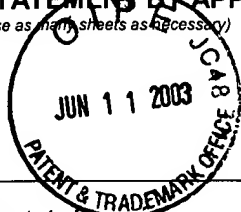


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Application Number	09/816602
Filing Date	March 23, 2001
First Named Inventor	Jensen, Mark
Group Art Unit	1745
Examiner Name	Winter, Gentle

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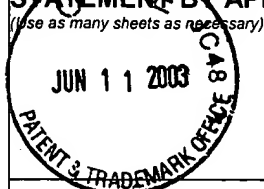
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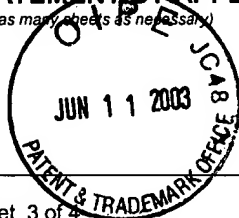
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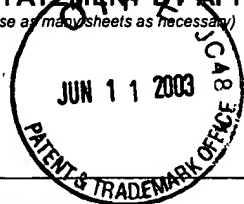
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